

| | | | | | |
|-----------------------------------|--|--|-------------------------------------|---|-------------|
| Notice of References Cited | | | Application/Control No. | Applicant(s)/Patent Under Reexamination OFFERLE ET AL. | |
| | | | Examiner Christopher P. Schwartz | Art Unit 3683 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-5,108,158 a | 04-1992 | Breen, Michael T. | 303/7 |
| | B | US-5,329,451 a | 07-1994 | Notsu, Ikurou | 701/41 |
| | C | US-5,411,322 a | 05-1995 | Breen, Michael T. | 303/7 |
| | D | US-5,461,357 a | 10-1995 | Yoshioka et al. | 340/435 |
| | E | US-5,747,683 | 05-1998 | Gerum et al. | 73/118.1 |
| | F | US-5,863,057 a | 01-1999 | Wessels, Larry L. | 280/149.2 |
| | G | US-6,292,094 b1 | 09-2001 | Deng et al. | 340/431 |
| | H | US-2002/0145663 a1 | 10-2002 | Mizusawa et al. | 348/118 |
| | I | US-6,704,637 b1 | 03-2004 | Hrazdera et al. | 701/93 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.